

**Search Notes**

Application/Control No.

10/028,402

Examiner

Nhon T. Diep

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2613

**SEARCHED**

Class	Subclass	Date	Examiner
375	240.03 240.12	6/13/05	MD
	240.18		
	240.19		
	240.22		
	240.23		
	240.24		MD
H04N	7/12	6/13/05	MD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR